

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/823,161	FRANK, MICHAEL	
Examiner		Art Unit		Page 1 of 1
CHIA-WEI A. CHEN		2622		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,334,829	08-1994	Ueno et al.	250/208.1
*	B	US-5,865,935	02-1999	Ozimek et al.	156/303.1
*	C	US-2003/0089957	05-2003	Anton, Marianne	257/433
*	D	US-4,420,261	12-1983	Barlow et al.	356/621
*	E	US-2003/0164365	09-2003	Ito et al.	219/444.1
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.